

Search Notes 	Application/Control No.	Applicant(s)/Patent under Reexamination
	09/494,514	NAVEEN ET AL.
	Examiner Michael W. Bowen	Art Unit 2625

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
Class & Text search US PAT, US PG-PUB 345/418-475, 581-689 348/445, 556, 571-721, 844, 913 382/108, 155-231, 254-308, 325 706/934 707/1-7, 104, 1	6/26/05	MWB
Search backward citation of US PAT 6,882,746 Naveen Note related application 09/495642	7/5/05	MWB
Text search: IEEE Xplore ACM	7/6/05	MWB
Text search on EAST: EPO, JPO, DERWENT	7/6/05	MWB

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner